

## Maximum Ratings Q1 N-CHANNEL (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Drain-Source Voltage	$V_{DSS}$	30	V		
Gate-Source Voltage	$V_{GSS}$	±20	V		
Continuous Drain Current (Note 6) V <sub>GS</sub> = 10V	I <sub>D</sub>	7.2 5.7	А		
Maximum Body Diode Forward Current (Note 6)	I <sub>S</sub>	2	Α		
Pulsed Drain Current (380µs Pulse, Duty Cycle = 1%	I <sub>DM</sub>	45	Α		
Avalanche Current (L = 0.1mH) (Note 7)			I <sub>AS</sub>	14	Α
Avalanche Energy (L = 0.1mH) (Note 7)			E <sub>AS</sub>	9.8	mJ

# Maximum Ratings Q2 P-CHANNEL (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Drain-Source Voltage	$V_{DSS}$	-30	V		
Gate-Source Voltage	V <sub>GSS</sub>	±20	V		
Continuous Drain Current (Note 6) V <sub>GS</sub> = -10V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I <sub>D</sub>	-6.8 -5.7	А
Maximum Body Diode Forward Current (Note 6)	I <sub>S</sub>	-2	Α		
Pulsed Drain Current (380µs Pulse, Duty Cycle = 1%	I <sub>DM</sub>	-40	Α		
Avalanche Current (L = 0.1mH) (Note 7)	I <sub>AS</sub>	-22	Α		
Avalanche Energy (L = 0.1mH) (Note 7)	E <sub>AS</sub>	24	mJ		

# Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)	$T_A = +25^{\circ}C$	$P_{D}$	1.2	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{ heta JA}$	105	°C/W
Total Power Dissipation (Note 6)	T <sub>A</sub> = +25°C	$P_{D}$	1.8	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{ heta JA}$	69	°C/W
Thermal Resistance, Junction to Case (Note 6)		$R_{ heta JC}$	15	°C/W
Operating and Storage Temperature Range		T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

Notes:

- 5. Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.
- 6. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.
- 7.  $I_{AS}$  and  $E_{AS}$  rating are based on low frequency and duty cycles to keep  $T_J = +25$ °C.



### Electrical Characteristics N-CHANNEL - Q1 (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	=	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	-	-	1	μΑ	$V_{DS} = 30V, V_{GS} = 0V$
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	1.0	-	2.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
Static Drain-Source On-Resistance	D		15	25	mΩ	$V_{GS} = 10V, I_D = 7A$
Static Dialii-Source Off-Resistance	R <sub>DS(ON)</sub>	ı	24	35	11122	$V_{GS} = 4.5V, I_D = 7A$
Diode Forward Voltage	$V_{SD}$	ı	0.70	1.0	<b>V</b>	$V_{GS} = 0V, I_{S} = 1A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	Ciss	-	500	_		$V_{DS} = 15V, V_{GS} = 0V,$ f = 1.0MHz
Output Capacitance	Coss	-	72	-	pF	
Reverse Transfer Capacitance	$C_{rss}$	-	57	=		
Gate resistance	$R_g$	-	1.9	=	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V <sub>GS</sub> = 4.5V)	$Q_{g}$	-	4.6	-		V <sub>DS</sub> = 15V, I <sub>D</sub> = 10A
Total Gate Charge (V <sub>GS</sub> = 10V)	Qg	-	9.8	=	nC	
Gate-Source Charge	Q <sub>gs</sub>	-	1.6	-	IIC	
Gate-Drain Charge	$Q_{gd}$	-	2.0	-		
Turn-On Delay Time	t <sub>D(ON)</sub>	-	3.9	-		$\begin{split} V_{DD} &= 15 V, \ V_{GS} = 10 V, \\ R_g &= 6 \Omega, \ I_D = 1 A \end{split}$
Turn-On Rise Time	t <sub>R</sub>	-	4.2	-		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	-	16.6	_	ns	
Turn-Off Fall Time	t <sub>F</sub>	-	5.8	-		
Reverse Recovery Time	t <sub>RR</sub>	-	5.6	_	ns	1 424 4:/44 5004/
Reverse Recovery Charge	Q <sub>RR</sub>		2.6		nC	I <sub>F</sub> = 12A, di/dt = 500A/μs

# Electrical Characteristics P-CHANNEL – Q2 (@TA = +25°C, unless otherwise specified.)

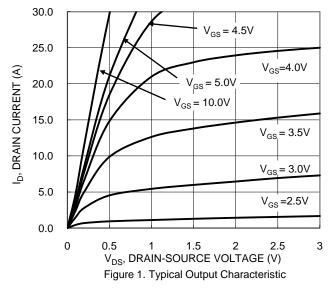
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-30	-	-	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	_	İ	-1	μA	$V_{DS} = -30V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	-	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	-1.2	-	-2.4	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
Static Drain-Source On-Resistance			22	28	mΩ	$V_{GS} = -10V, I_D = -7A$	
Static Diani-Source On-Resistance	R <sub>DS(ON)</sub>	_	32	38	11152	$V_{GS} = -4.5V$ , $I_{D} = -6.2A$	
Diode Forward Voltage	$V_{SD}$	_	-0.7	-1.2	V	$V_{GS} = 0V, I_{S} = -2.1A$	
DYNAMIC CHARACTERISTICS (Note 9)							
Input Capacitance	C <sub>iss</sub>	_	1,188	-		$V_{DS} = -15V, V_{GS} = 0V,$ f = 1MHz	
Output Capacitance	Coss	-	154	-	pF		
Reverse Transfer Capacitance	Crss	_	116	-			
Gate Resistance	Rg	_	9	=	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$	
Total Gate Charge (V <sub>GS</sub> = -4.5V)	Qg	_	9.5	-		$V_{DS} = -15V, I_{D} = -7A$	
Total Gate Charge (V <sub>GS</sub> = -10V)	Qg	_	19.7	=	nC		
Gate-Source Charge	Qgs	_	3.1	=	IIC		
Gate-Drain Charge	$Q_{gd}$	_	3.2	=			
Turn-On Delay Time	t <sub>D(ON)</sub>	-	3.7	-		$V_{GS} = -10V, V_{DS} = -15V,$ $R_g = 6\Omega, I_D = -7A$	
Turn-On Rise Time	t <sub>R</sub>	-	2.6	-			
Turn-Off Delay Time	t <sub>D(OFF)</sub>	-	36	-	ns		
Turn-Off Fall Time	t <sub>F</sub>	-	22	-			
Reverse Recovery Time	t <sub>RR</sub>	-	10.4	-	ns	1 70 4:/4+ 4000/	
Reverse Recovery Charge	Q <sub>RR</sub>	_	3.2	=	nC	$I_F = -7A$ , di/dt = 100A/ $\mu$ s	

Notes: 8. Short duration pulse test used to minimize self-heating effect.

<sup>9.</sup> Guaranteed by design. Not subject to product testing.



### **Typical Characteristics - N-CHANNEL**



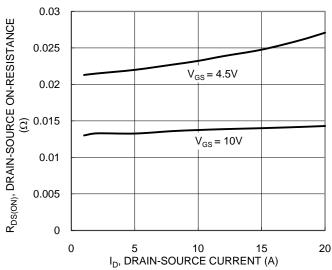


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

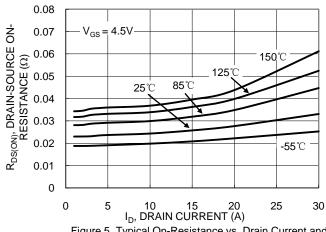


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

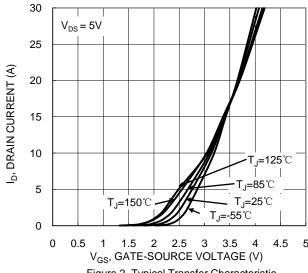


Figure 2. Typical Transfer Characteristic

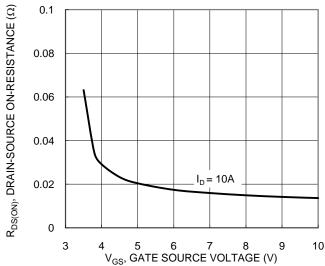


Figure 4. Typical On-Resistance vs. Drain Current and Gate Voltage

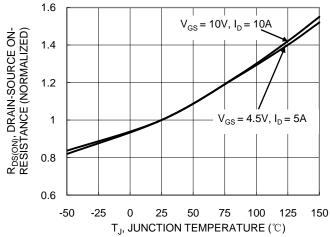


Figure 6. On-Resistance Variation with Temperature



### Typical Characteristics - N-CHANNEL (Cont.)

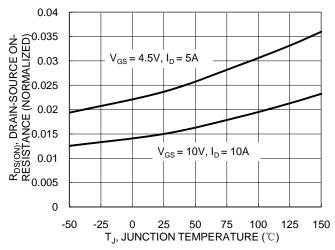


Figure 7. On-Resistance Variation with Temperature

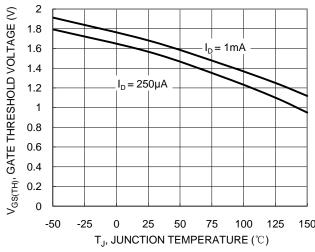
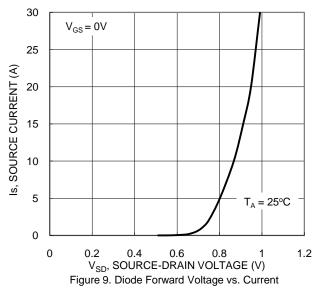
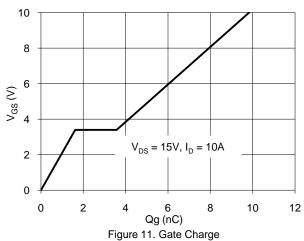
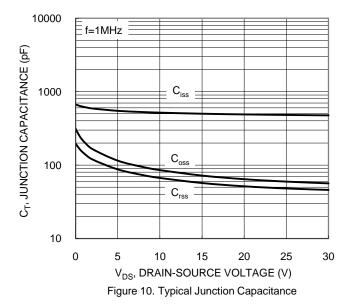


Figure 8. Gate Threshold Variation vs. Junction Temperature



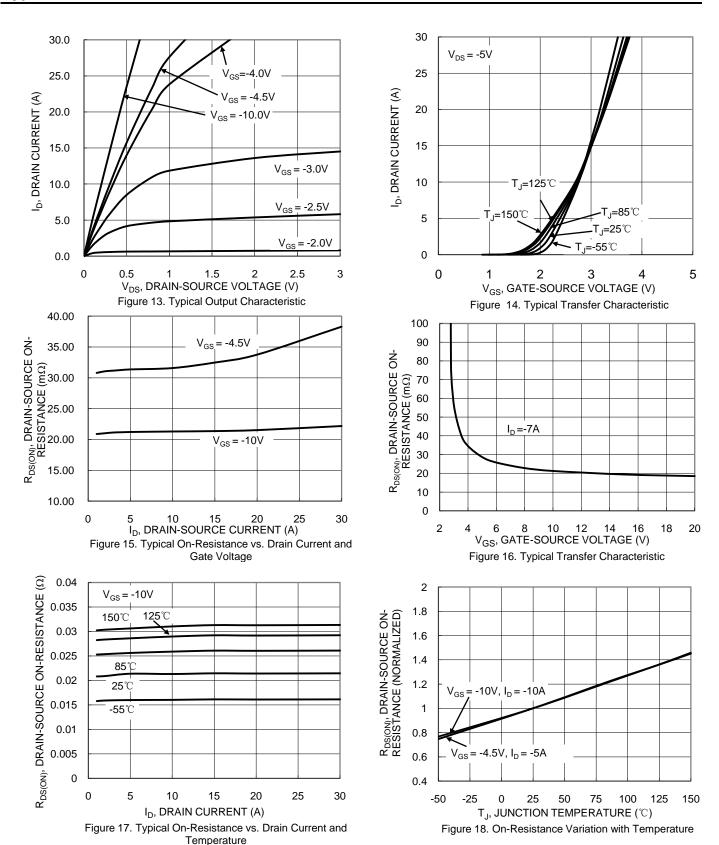




100 R<sub>DS(ON)</sub> Limited ID, DRAIN CURRENT (A) 10 1  $P_W = 10 \text{ms}$ ⊤ P<sub>w</sub> =100ms T<sub>J(Max)</sub> = 150°C 0.1 T<sub>C</sub> = 25 °C Single Pulse
DUT on 1\*MRP Board V<sub>GS</sub>= 10V 0.01 0.1 10 100 V<sub>DS</sub>, DRAIN-SOURCE VOLTAGE (V) Figure 12. SOA, Safe Operation Area



#### **Typical Characteristics - P-CHANNEL**





#### Typical Characteristics - P-CHANNEL (Cont.)

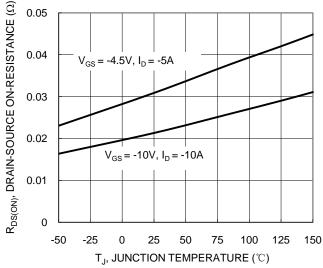
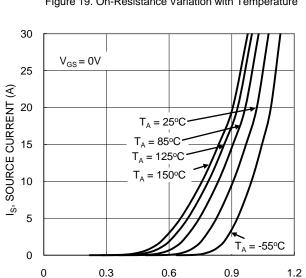


Figure 19. On-Resistance Variation with Temperature



V<sub>SD</sub>, SOURCE-DRAIN VOLTAGE (V) Figure 21. Diode Forward Voltage vs. Current

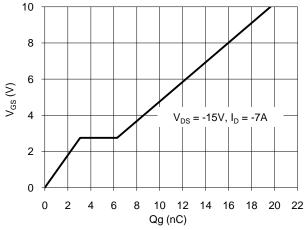


Figure 23. Gate Charge

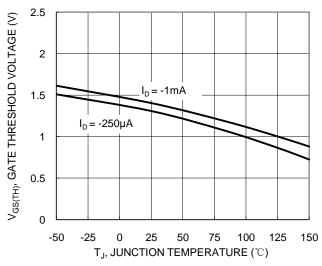
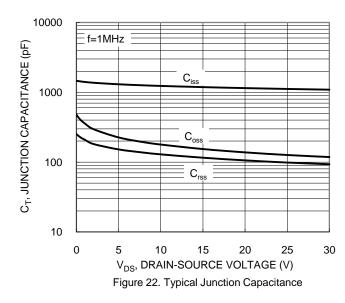
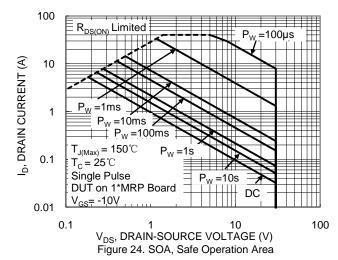


Figure 20. Gate Threshold Variation vs. Junction Temperature







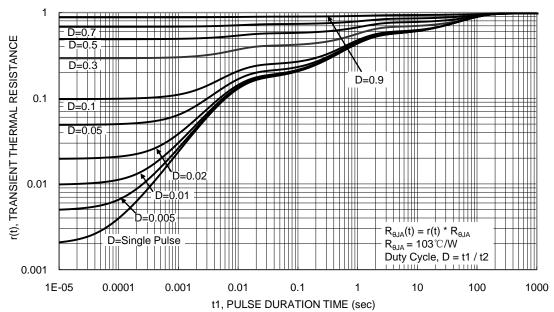


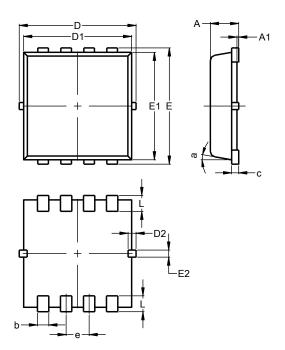
Figure 25. Transient Thermal Resistance



## **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### POWERDI<sup>®</sup>3333-8 (Type UXB)

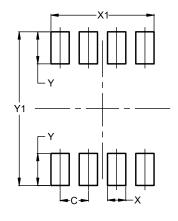


POWERDI®3333-8							
(Type UXB)							
Dim	Min	Max	Тур				
Α	0.75	0.85	0.80				
<b>A</b> 1	0.00	0.05	_				
b	0.25	0.40	0.32				
С	0.10	0.25	0.15				
D	3.20	3.40	3.30				
D1	2.95	3.15	3.05				
D2	0.10	0.35	0.23				
Е	3.20	3.40	3.30				
E1	2.95	3.15	3.05				
E2	0.10	0.30	0.20				
е	_	_	0.65				
L	0.35	0.55	0.45				
а	0°	12°	10°				
All Dimensions in mm							

## **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### POWERDI®3333-8 (Type UXB)



Dimensions	Value (in mm)
С	0.650
Х	0.420
X1	2.370
Y	0.730
Y1	3.500



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